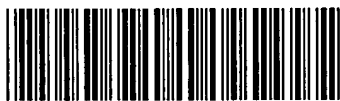


Search Notes

Application/Control No.

10/766,208

Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

FURUKAWA ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	745	3/28/2007	LVN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/745		3/28/2007	LVN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventor name search	3/28/2007	LVN
US-PGPub, USPAT: 715/745,748,742; 705/400-411,64; 709/206	3/28/2007	LVN